

TEC-QEC Final Presentation days

Thursday, 29 June 2023

Session 3: Technology Studies - ESTEC - Tennis Hall (11:55 - 16:15)

-Conveners: Christian POIVEY

time	[id] title	presenter
11:55	[1] Lessons learned for SDRAM testing	BOUNASSER, Said
12:20	Lunch Break	
14:00	[35] Part 1: Estimation of proton induced single event rate in very deep submicron technologies	JAVANAINEN, Arto TANIOS, Bendy
14:20	[8] Part 2: Estimation of proton induced single event rate in very deep submicron technologies	ARTOLA, Laurent GLORIEUX, Maximilien
14:40	[38] MOSFET Commercial plastic components survey (Trenchfet,...) and its SEE characterization	ROMERO MADERA, Fernando LARGAESPADA GÓMEZ, José Francisco
15:00	[13] Part 1: Radiation screening of COTS components and verification of COTS RHA approach	TSCHERNE, Christoph BECK, Peter
15:20	[37] Part 2: Radiation screening of COTS components and verification of COTS RHA approach	BAGATIN, Marta GERARDIN, Simone
15:40	Coffee Break	